09/845,562

| L Number | Llite | Coard Tout | DB | Time at an |
|----------|---------|---|-----------|------------------|
| | Hits | Search Text | DB | Time stamp |
| 1 | 3972123 | integrated circuit with dual mode test access port\$1 | USPAT; | 2004/02/17 10:34 |
| İ | | | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 2 | 3009849 | data register\$1 | USPAT; | 2004/02/17 10:35 |
|] | | | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 3 | 1243909 | (integrated circuit with dual mode test access port\$1) and (data | USPAT; | 2004/02/17 10:36 |
| | | register\$1) | US-PGPUB; | |
| ļ | | | EPO; JPO; | , |
| | 1 | | DERWENT; | |
| | | | IBM_TDB | |
| 4 | 2495028 | intellectual property core\$1 | USPAT; | 2004/02/17 10:37 |
| | | | US-PGPUB; | ,, |
| 1 | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 5 | 2078445 | externally accessible scan path\$1 | USPAT; | 2004/02/17 10:37 |
| | 20/0113 | executarly accessible scarr pacrist | US-PGPUB; | 2007/02/17 10.37 |
| ŀ | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | , | IBM_TDB | |
| ا د | 421000 | (intellectual property corett) and (externally perceptible core | _ | 2004/02/17 10:27 |
| 6 | 431880 | (intellectual property core\$1) and (externally accessible scan | USPAT; | 2004/02/17 10:37 |
| | | path\$1) | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| _ | 4.600=0 | | IBM_TDB | |
| 7 | 169853 | ((intellectual property core\$1) and (externally accessible scan | USPAT; | 2004/02/17 10:40 |
| | | path\$1)) and ((integrated circuit with dual mode test access | US-PGPUB; | |
| | | port\$1) and (data register\$1)) | EPO; JPO; | |
| | | | DERWENT; | |
| _ | | | IBM_TDB | |
| 8 | 46 | "IEEE 1149.1 TAP" | USPAT; | 2004/02/17 10:41 |
| ĺ | | | US-PGPUB; | |
| j | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 9 | 33 | (((intellectual property core\$1) and (externally accessible scan | USPAT; | 2004/02/17 10:42 |
| | | path\$1)) and ((integrated circuit with dual mode test access | US-PGPUB; | |
| | | port\$1) and (data register\$1))) and "IEEE 1149.1 TAP" | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 11 | 5470459 | enabl\$3 signal\$1 | USPAT; | 2004/02/17 10:43 |
| | | - | US-PGPUB; | |
| | • | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 12 | 3709152 | disabl\$3 signal\$1 | USPAT; | 2004/02/17 10:43 |
| | - · | | US-PGPUB; | |
| j l | ! | | EPO; JPO; | |
| | ı | | DERWENT; | |
| | | | IBM_TDB | |
| 13 | 3681902 | (enabl\$3 signal\$1) and (disabl\$3 signal\$1) | USPAT; | 2004/02/17 10:45 |
| | 3301302 | (anadigo digitaliga) and (albabigo digitaliga) | US-PGPUB; | 2007/02/17 10:43 |
| l İ | | | EPO; JPO; | |
| | | | DERWENT; | · |
| | | | | |
| tl | | I | IBM_TDB | <u> </u> |

| 14 | 722 | ((((intellectual preparty corett) and (oxternally accessible sean | LICDAT | 2004/02/17 10:49 |
|-----|---------|--|-----------|----------------------|
| 14 | 33 | ((((intellectual property core\$1) and (externally accessible scan path\$1)) and ((integrated circuit with dual mode test access | USPAT; | 2004/02/17 10:48 |
| | | | US-PGPUB; | |
| | | port\$1) and (data register\$1))) and "IEEE 1149.1 TAP") and | EPO; JPO; | |
| | | ((enabl\$3 signal\$1) and (disabl\$3 signal\$1)) | DERWENT; | |
| | | | IBM_TDB | |
| 15 | 1974031 | TAP test interface | USPAT; | 2004/02/17 10:49 |
| | | | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | , |
| | | | IBM_TDB | |
| 16 | 2214968 | alternate test interface | USPAT; | 2004/02/17 10:49 |
| | | | US-PGPUB: | 200 1, 02, 27 201 15 |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 17 | 1062022 | (TAD test interfere) and (alternate test interfere) | | 2004/02/17 10:50 |
| 17 | 1863922 | (TAP test interface) and (alternate test interface) | USPAT; | 2004/02/17 10:50 |
| | | | US-PGPUB; | |
| | | | EPO; JPO; | * |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 18 | 33 | | USPAT; | 2004/02/17 10:50 |
| | | path\$1)) and ((integrated circuit with dual mode test access | US-PGPUB; | |
| | | port\$1) and (data register\$1))) and "IEEE 1149.1 TAP") and | EPO; JPO; | |
| | | ((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test | DERWENT; | |
| | | interface) and (alternate test interface)) | IBM_TDB | |
| 19 | 3163057 | scan data register\$1 | USPAT; | 2004/02/17 10:50 |
| 1.5 | 3103037 | Scarr data register #1 | US-PGPUB; | 200-1/02/17 10:50 |
| | | | EPO; JPO; | |
| | | | | |
| | | | DERWENT; | |
| | | l | IBM_TDB | |
| 20 | 1123817 | boundary scan register\$1 | USPAT; | 2004/02/17 10:50 |
| | | | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | j | | IBM_TDB | |
| 21 | 684272 | bypass register\$1 | USPAT; | 2004/02/17 10:50 |
| | | | US-PGPUB; | |
| | | | EPO; JPO; | , |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 22 | 904426 | (boundary scan register\$1) and (scan data register\$1) | USPAT; | 2004/02/17 10:52 |
| 22 | 301720 | (bodildary scall registers) and (scall data registers) | US-PGPUB; | 2007/02/17 10.32 |
| | | | | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| 22 | F40004 | // | IBM_TDB | 2004/02/45 40 55 |
| 23 | 542391 | (bypass register\$1) and ((boundary scan register\$1) and (scan | USPAT; | 2004/02/17 10:52 |
| | | data register\$1)) | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 24 | 881375 | instruction register\$1 | USPAT; | 2004/02/17 10:54 |
| | | | US-PGPUB; | |
| | - | | EPO; JPO; | |
| | | | DERWENT; | |
| | | | | |
| 25 | F27420 | //hunner registeret1) and //harmdam. seem or sisteret4) and / | IBM_TDB | 2004/02/17 10:55 |
| 25 | 537439 | ((bypass register\$1) and ((boundary scan register\$1) and (scan | USPAT; | 2004/02/17 10:55 |
| | | data register\$1))) and (instruction register\$1) | US-PGPUB; | |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| | 1 | 1 | IBM_TDB | 1 |

| 26 | 7 | 1 | 11004= | T 2004/20/47 48 == |
|----|---------|---|------------------------|--------------------|
| 26 | 24 | (((bypass register\$1) and ((boundary scan register\$1) and (scan data register\$1)) and (instruction register\$1)) and | USPAT; US-PGPUB; | 2004/02/17 10:55 |
| | | ((((((intellectual property core\$1) and (externally accessible scan | EPO; JPO; | |
| | | path\$1)) and ((integrated circuit with dual mode test access | DERWENT; | |
| | | port\$1) and (data register\$1))) and "IEEE 1149.1 TAP") and | IBM_TDB | |
| | | ((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test | | |
| ^= | 5040000 | interface) and (alternate test interface))) | | |
| 27 | 5048293 | first protocol | USPAT; | 2004/02/17 10:55 |
| | | | US-PGPUB; EPO; JPO; | |
| | | | DERWENT; | |
| | | | IBM_TDB | |
| 28 | 4740324 | second protocol | USPAT; | 2004/02/17 10:55 |
| | | · | US-PGPUB; | ,, |
| | | | EPO; JPO; | |
| | | | DERWENT; | |
| 20 | 4205526 | | IBM_TDB | |
| 29 | 4205536 | (first protocol) and (second protocol) | USPAT; | 2004/02/17 10:57 |
| | | | US-PGPUB; | |
| | | | EPO; JPO; DERWENT; | |
| | | | IBM_TDB | |
| 30 | 24 | ((((bypass register\$1) and ((boundary scan register\$1) and (scan | USPAT; | 2004/02/17 10:59 |
| | | data register\$1))) and (instruction register\$1)) and | US-PGPUB; | ==== ,, ==, ===== |
| | | ((((((intellectual property core\$1) and (externally accessible scan | EPO; JPO; | |
| | | path\$1)) and ((integrated circuit with dual mode test access | DERWENT; | |
| | | port\$1) and (data register\$1))) and "IEEE 1149.1 TAP") and | IBM_TDB | |
| | | ((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test | | |
| | | interface) and (alternate test interface)))) and ((first protocol) and | | |
| | | (second protocol)) | 1 | 1 |